

# P. P. SAVANI UNIVERSITY

Fifth Semester of B.Sc. Examination  
December-2021

SSCH3210-Applied Chemistry- Microscopy Techniques

15.12.2021, Wednesday Time: 12:30 a.m. to 03:00 p.m. Maximum Marks: 60

## Instructions:

1. The question paper comprises of two sections.
2. Section I and II must be attempted in separate answer sheets.
3. Make suitable assumptions and draw neat figures wherever required.
4. Use of scientific calculator is allowed.

### Section-I (Total Marks - 30)

Q.1 Short Questions [10]

1.1 Objectives [05]

1.1a Magnification depends on

- A length,
- B breadth
- C diameter
- D All of the above

1.1b How many types of aberration are there

- A 2
- B 3
- C 1
- D 4

1.1c How many types of Light microscope

- A 4
- B 3
- C 1
- D 2

1.1d For bright field microscope

- A Staining is required
- B Staining is not required
- C Staining not destroys the biological sample
- D B & C are correct

1.1e Properties of TEM microscope

- A Stream of electrons is formed
- B Accelerated using a positive electrical potential
- C Focused by metallic aperture and Electro magnets
- D All of the above are correct

1.1f For SEM

- A Specimen must be very thin
- B Wide range of specimens allowed

- C Broad, static beams
- D Electrons must pass through and be transmitted by the specimen

**1.1g Properties of Polarizing Microscope**

- A Uses two Polariser
- B Gives information about Birefringence of a body
- C Used in Crystallography
- D All of the above are correct

**1.1h DIC uses**

- A IR light
- B UV light
- C Visible light
- D Far-IR light

**1.1i Geometrical optics**

- A the study of light as rays
- B the study of light as waves
- C the study of light as particles
- D All of the above are correct

**1.1j the study of the wave properties of light involves**

- A Interference
- B Diffraction
- C Polarization
- D All of the above

**1.2 Answer the Following: (MCQ/Short Question/Fill in the Blanks)**

[05]

- 1.2a The surface features of an object is called \_\_\_\_\_ ?
- 1.2b What is Auger effect?
- 1.2c Name the detector used in SEM microscope?
- 1.2d Write the one application of SEM?
- 1.2e What is BSE?

**Q.2 Short Notes (Attempt any two)**

[06]

- A Discuss about the secondary electron generation of SEM?
- B What is resolution and Numerical aperture of a microscope and discuss how they are related to each other?
- C Write about the advantages and disadvantages of compound microscope?

**Q.3 Explain in detail (Attempt any two)**

[14]

- A Explain, what happens when electron beam strikes the specimen with diagrams?
- B Define the term magnification, resolution, definition, law of reflection and optics of microscope? Calculate the total magnification of a microscope, if the magnification of eye piece and objective are 20X and 30X?
- C Discuss the principle, application of DIC microscopy and draw the diagram showing the journey of light in DIC?



**Section-II (Total Marks - 30)**

**Q.1 Short Questions**

**[10]**

**1.1 Objectives**

**[05]**

**1.1a Full form of LFM**

- A Lateral force microscopy
- B Atomic force microscopy
- C Longitudinal force microscope
- D B & C are correct

**1.1b Tapping mode of AFM**

- A High Resolution
- B Slower speed
- C Constant force between tip and surface
- D All are correct

**1.1c Non-contact mode of AFM**

- A Lower resolution
- B Slower Speed
- C No damage to tip
- D All are correct

**1.1d The difference between tip and sample in contact mode of AFM**

- A < 0.5 nm
- B 0.5- 2 nm
- C 0.1-10 nm
- D B and C are correct

**1.1e Application of AFM**

- A Material science
- B Polymer Science
- C Data storage
- D All are correct

**1.1f Name the material which is used for photographic screen of TEM**

- A Zinc Sulphide
- B Manganese dioxide
- C Copper Oxide
- D Titanium dioxide

**1.1g In AFM, Fabrication of cantilever requires**

- A Soft and high sensitive
- B Hard and high sensitive
- C Soft and low sensitive
- D Hard and low sensitive

- 1.1h** Objective lens of TEM is
- A Strong lens
  - B Weak lens
  - C Moderate lens
  - D Both B & C are correct

- 1.1i** In AFM, Fabrication of Tip
- A Si<sub>3</sub>N<sub>4</sub>
  - B ZnO
  - C TiO<sub>2</sub>
  - D Fe<sub>2</sub>O<sub>3</sub>

- 1.1j** TEM consists of
- A Electron source
  - B Condenser lens
  - C Objective lens with aperture
  - D All are correct

**1.2 Answer the Following: (MCQ/Short Question/Fill in the Blanks)** [05]

- 1.2a** Give one difference between light microscope and electron microscope?
- 1.2b** Calculate the total magnification of a microscope?
- 1.2c** In TEM, screen emits \_\_\_\_\_ when bombarded with electrons.
- 1.2d** What is the full form of TEM?
- 1.2e** What is the full form of SEM?

**Q.2 Short Notes (Attempt any two)** [06]

- A Discuss about lateral force Microscopy?
- B Discuss about working mode of TEM?
- C Discuss about contact mode of AFM?

**Q.3 Explain in detail (Attempt any two)** [14]

- A Draw the schematic diagram of Beam and Specimen Interaction of TEM? State the principle of TEM?
- B Discuss about the working mode of AFM? Discuss about its mode of imaging of constant height and constant force of AFM?
- C Describe the tapping and non-contact mode of AFM?